

Search for Supersymmetry at CMS in Events with Two Photons and Missing Transverse Energy at $\sqrt{s} = 13$ TeV (**CADI:SUS-15-012**)

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PHENO 2016
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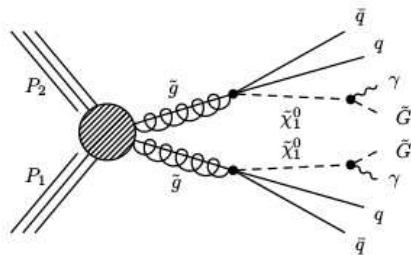
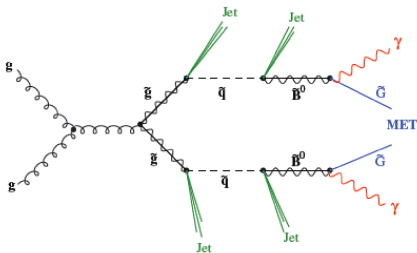
Florida State University

May 9, 2016



Supersymmetry (SUSY) and Gauge Mediated Supersymmetry Breaking (GMSB):

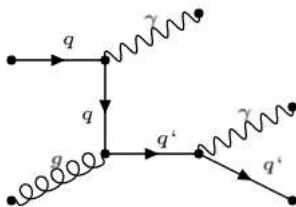
- Symmetry between SM bosons and fermions to supersymmetric fermions and bosons.
- Broken symmetry: otherwise the SM particle and its SUSY partner would have the same mass
 - GMSB:
 - Ordinary gauge interaction is responsible for SUSY breaking.



- Quantum Chromodynamics (QCD) background
 - May have two real photons in the final state, or one or both coming from the electromagnetically-rich jet fragmentation mimicking the response of a photon.
 - Missing transverse energy (E_T^{miss} or MET) from object mis-measurement.

QCD Background

Most significant background as the QCD cross-section is enormous!

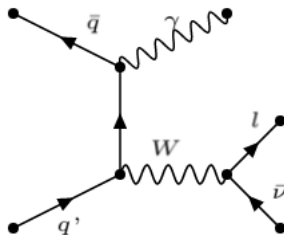


- Electroweak (EWK) background
 - SM process with neutrino in the final state.
 - $W\gamma$, W -jets events where $W \rightarrow e\nu$ etc.

EWK Background

genuine E_T^{miss} , but very small background.

- Other negligible contributions:
 $Z\gamma\gamma \rightarrow \nu\bar{\nu}\gamma\gamma$, $W\gamma\gamma \rightarrow l\nu\gamma\gamma$, $t\bar{t}\gamma\gamma$.



Candidate (Double Photon, $\gamma\gamma$) Sample

- Define $\Delta R = \sqrt{(\Delta\eta)^2 + (\Delta\phi)^2}$
- Hadronic energy deposition (H)/
electromagnetic energy deposition(E)
< 0.05 around the photon object.
- Showershape in η direction should be
consistent with electromagnetic
shower.
- No hit in inner two layers of silicon
pixel detector.
- The selected objects should be well
isolated. Applied particle-flow based
isolation.
- The photon selection follows medium
cut based photon Id.

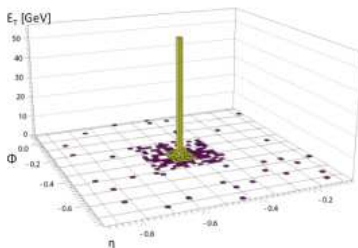


Figure : A sample photon deposition in the detector.



Control samples for QCD background estimation

- **Electron (ee) Sample**
 - Selection of electron: same as photon selection but requires hit in the silicon pixel detector.
 - Two separated electrons having invariant mass within 75 to 105 GeV (within Z boson mass).
- **Fake (ff) Sample**
 - Comes primarily from electromagnetically rich jets whose fragmentation mimic the response of photons.
 - The requirement of deposited transverse momenta by charged hadrons around the object within $\Delta R < 0.3$ or the shower shape in η direction (but **NOT** both) is orthogonal to that of photon selection.
- These samples don't have real E_T^{miss} , ideal for QCD background modeling.

Control sample for EWK background estimation:

- **Electron-Photon ($e\gamma$) sample:** events with one electron and one photon.
- Real E_T^{miss} .

High Level Trigger:

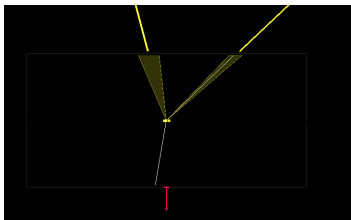
- Two objects with leading object $p_T > 30$ GeV and sub-leading object $p_T > 18$ GeV.
- Shower shape for each object must be less than 0.015 for the barrel and also $H/E < 0.1$.
- The objects should be isolated.
- Invariant mass > 95 GeV.



- Imbalance in the total transverse momentum of particles before and after collision.
 - May be due to object mis-measurement.
 - Particles leaving the detector undetected.

Definition

$E_T^{miss} = -\sum_{i=1}^n \vec{p}_{T_i}$ where i runs over all visible particles in the event.



E_T^{miss}

Toughest thing to measure because it involves resolution of all the visible particles!

- Correction to E_T^{miss} :
 - Type 0 correction: correction on E_T^{miss} to reduce the effect of pileup.
 - Type 1 correction: the propagation of correction applied to the jets.

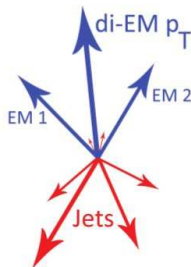


Double-Photon Sample

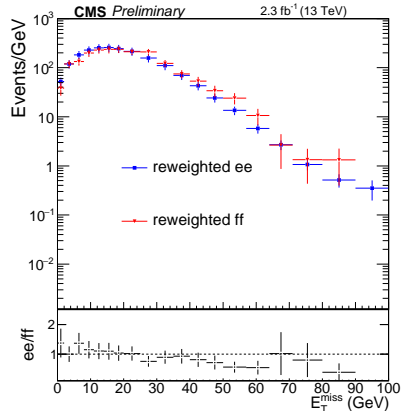
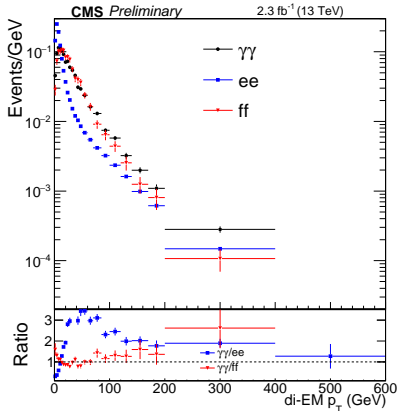
- Any double-photon sample selected will invariably contain jet-jet, photon-jet samples because of jet fluctuations appearing as photons.
- Very tough to simulate the E_T^{miss} distribution when jets fluctuate and appear as photons, as resolution in measuring jets are poor.
- Even with events with two true photons, mis-measurement of the E_T^{miss} possible due to the additional hadronic activity.
- Data-driven technique: control sample with ee and ff because they don't have real E_T^{miss} .
- Control samples differ from candidate samples in hadronic activity.

di-EM p_T :

- di-EM p_T is defined as transverse momenta of two electromagnetic objects:
 $\vec{p}_T^{di-EM} = (\vec{p}_{T1} + \vec{p}_{T2})$ where \vec{p}_{T1} and \vec{p}_{T2} are the individual transverse momentum of the electromagnetic objects.
- This is a measure of hadronic recoil in the sample.



Modeling QCD Background: Di-EM p_T Reweighting

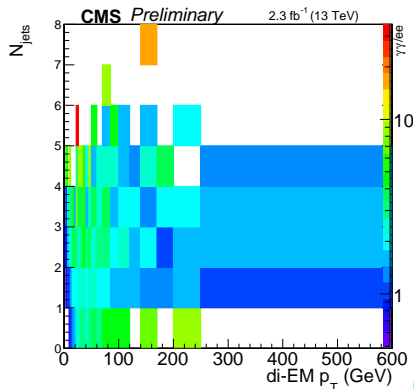
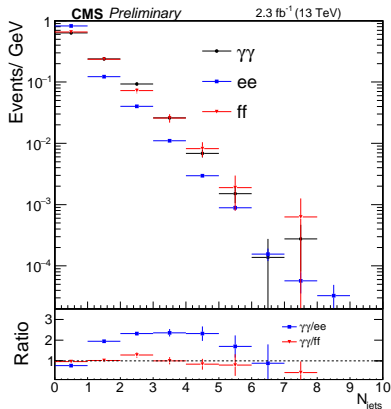


- The primary QCD background estimate comes from the double electron sample.
- The prediction from double fake samples used to cross check our double electron estimate.



Modeling QCD Background: Jet multiplicity distribution

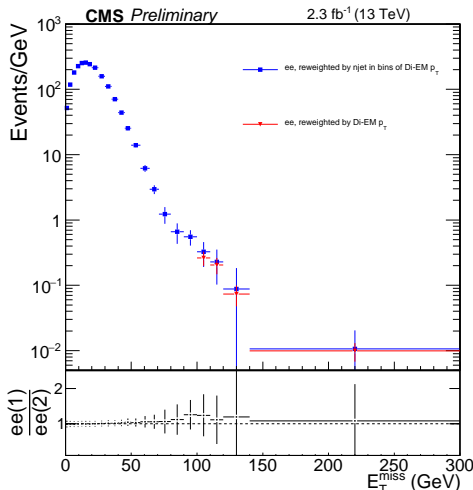
- E_T^{miss} distribution between control and candidate samples can differ because of difference in jet multiplicity.
- The energy resolution in an event where there are three jets having total p_T of 100 GeV will be worse than that of an event where there is only one jet having p_T of 100 GeV.
- To extract any dependence of jet multiplicity with di-EM p_T for ee sample, the jet multiplicity is plotted in bins of di-EM p_T .



Effect of reweighting by jet multiplicity distribution:

- To know the effect of jet multiplicity reweighting, we plot only di-EM p_T reweighted ee E_T^{miss} and jet multiplicity in bins of di-EM p_T reweighted ee E_T^{miss} .
- The ratio shows the effect of jet multiplicity reweighting is small.
- Take the difference between only di-EM p_T reweighted ee E_T^{miss} and jet multiplicity in bins of di-EM p_T reweighted ee E_T^{miss} as one of our systematic uncertainties.

E_T^{miss} bin (GeV)	Expected QCD (from reweighted ee)
100 – 110	1.85 ± 0.96
110 – 120	1.53 ± 0.63
120 – 140	0.97 ± 0.62
> 140	0.61 ± 2.15

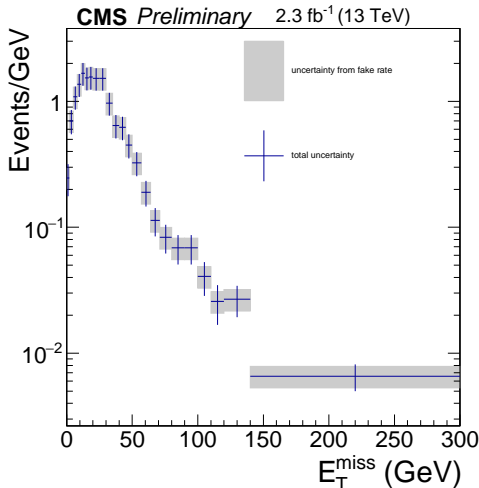


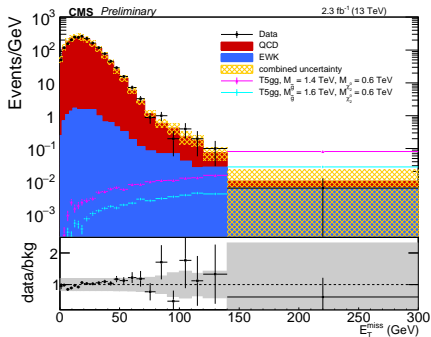
EWK Background:

- Coming mainly from $W\gamma$ sample where $W \rightarrow e\nu$ and electron is misidentified as photon, so we get double-photon final state.

- To model the EWK background, need to find the electron-to-photon misidentification rate (fake rate) ($f_{e \rightarrow \gamma}$) and scale the electron-photon E_T^{miss} distribution with it.
- $f_{e \rightarrow \gamma} = 0.021 \pm 0.002$
- $N_{\gamma\gamma} = \frac{f_{e \rightarrow \gamma}}{1 - f_{e \rightarrow \gamma}} N_{e\gamma}$
- $M_{e\gamma} > 105 \text{ GeV}$.

E_T^{miss} bin (GeV)	Expected EWK
100 – 110	0.41 ± 0.12
110 – 120	0.26 ± 0.09
120 – 140	0.54 ± 0.15
> 140	1.03 ± 0.25





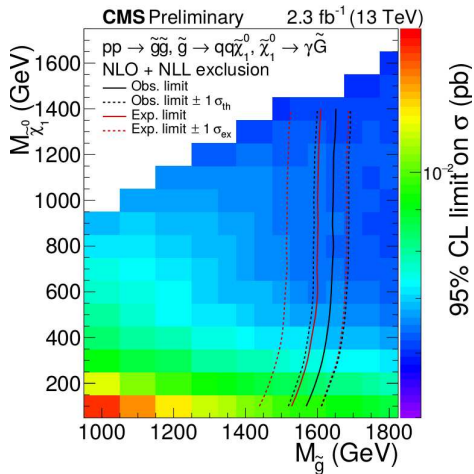
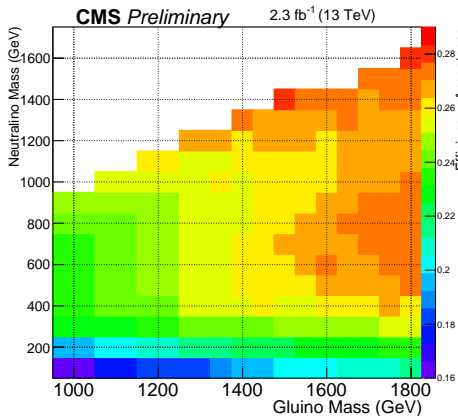
E_T^{miss} bin (GeV)	Expected QCD+EWK	Observed
100 – 110	2.26 ± 0.96	4
110 – 120	1.79 ± 0.64	2
120 – 140	1.51 ± 0.64	2
> 140	1.64 ± 2.16	1

Table : Expected and observed events for $E_T^{miss} > 100$ GeV

Remark:

- Did not get significantly excess events over expected background in data.
- Put the limits on production cross sections.





- Efficiency \times Acceptance is low for low gluino and neutralino masses, as here most of the photons fail to pass $p_T > 40$ GeV cut.



- Full analysis done on 13 TeV data.
- Successfully modeled the background for the analysis.
- Did not observe any significantly excess event in the signal region.
- The analysis with 8 TeV data (integrated luminosity 19.6 fb^{-1}) set limits on gluino mass at 1.35 TeV (arxiv:1507.02898). With only 2.3 fb^{-1} of 13 TeV data, the limits on gluino mass is extended to 1.65 TeV.



- Thank You!



- Back Up



Trigger:

- Primary analysis trigger: *HLT_Diphoton30_18_R9Id_OR_IsoCalold_AND_HE_R9Id_Mass95_v**.
- Lead photon $p_T > 30$ GeV and trail photon $p_T > 18$ GeV.
- Leading leg has L1 seed, but sub-leading leg is unseeded.
- $M_{\gamma\gamma} > 95$ GeV.
- Photons must pass *_HE_R9Id_* and (*_R9Id_* or *_IsoCalold_*).

<i>_R9Id_</i>	$R9 > 0.85$
<i>_IsoCalold_</i>	$\sigma_{i\eta i\eta} < 0.015$ ECAL Isolation $< (6 + 0.012 \times p_T^\gamma)$ Track Isolation $< (6 + 0.002 \times p_T^\gamma)$
<i>_HE_R9Id_</i>	$H/E < 0.1$ $R9 > 0.5$

High Level Trigger

- *HLT_Diphoton30_18_R9Id_OR_IsoCalold_AND_HE_R9Id_Mass95_v**
- *HLT_Diphoton30_18_R9Id_OR_IsoCalold_AND_HE_R9Id_DoublePixelSeedMatch_Mass70_v**
- *HLT_Diphoton30PV_18PV_R9Id_AND_IsoCalold_AND_HE_R9Id_DoublePixelVeto_Mass55_v**
- *HLT_Diphoton30EB_18EB_R9Id_OR_IsoCalold_AND_HE_R9Id_DoublePixelVeto_Mass55_v**



Trigger efficiencies:

- Trigger requires two photons passing sub-leading filters and one photon passing leading filters.
- Total trigger efficiency $\epsilon_{tot} = \epsilon_{lead,lead} \times \epsilon_{lead,sub} \times \epsilon_{sub,sub}$
- $\epsilon_{lead,lead}$ means efficiency of leading photon passing leading filter.
- $\epsilon_{lead,sub}$ means efficiency of leading photon passing sub-leading filter.
- $\epsilon_{sub,sub}$ means efficiency of sub-leading photon passing sub-leading filter.

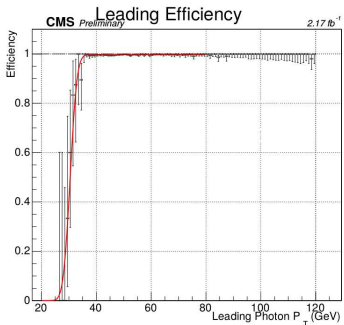


Figure : Efficiency of leading photon passing leading filter as function of photon p_T

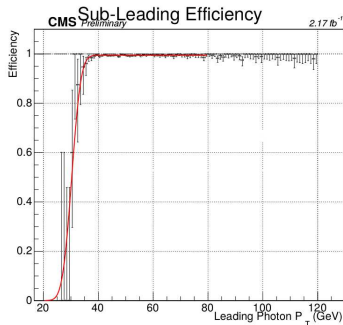


Figure : Efficiency of leading photon passing sub-leading filter as function of photon p_T



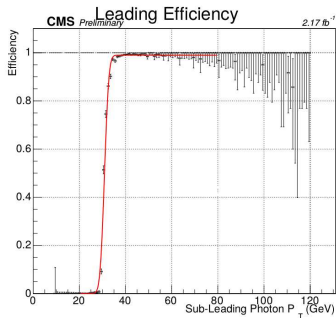


Figure : Efficiency of sub-leading photon passing leading filter as function of photon p_T

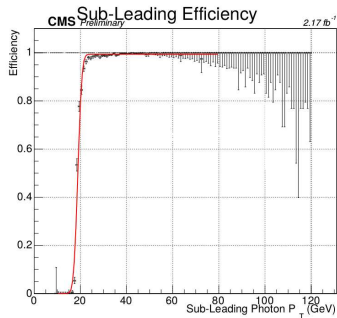


Figure : Efficiency of sub-leading photon passing sub-leading filter as function of photon p_T

- We use the photon p_T cut at 40 GeV.
- At this point, $\epsilon_{lead,lead} = 0.997$, $\epsilon_{lead,sub} = 0.995$
- $\epsilon_{sub,sub} = 0.994$, $\epsilon_{tot} = 98.6\%$

- Determine the ID efficiency of $e\gamma$ objects.
- Photon efficiency $\epsilon_\gamma = \epsilon_\gamma^{MC} \times \frac{\epsilon_e^{data}}{\epsilon_e^{MC}}$
- Computed the efficiency as a function of kinematic variables like: E_T , $|\eta|$, $\Delta R(\gamma, jet)$.
- Data used: DoubleEG streams (Run C and Run D)
- Trigger used: *HLT_Diphoton30_18_R9Id_OR_IsoCalold_AND_HE_R9Id_DoublePixelSeedMatch_Mass70_v**
- MC sample: DY \rightarrow ee sample (*DYToEE_13TeV - amcatnloFXFX - pythia8*)
- γ selection:
 - $|\eta| < 2.5$, $E_T > 25$ GeV for probe, $E_T > 35$ GeV for tag
 - tagged photon passes tight photon selection
 - probe efficiencies were computed for loose, medium and tight selections.



Scale factors:

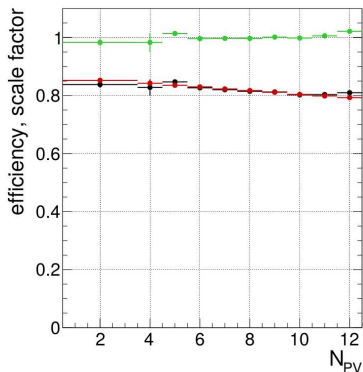
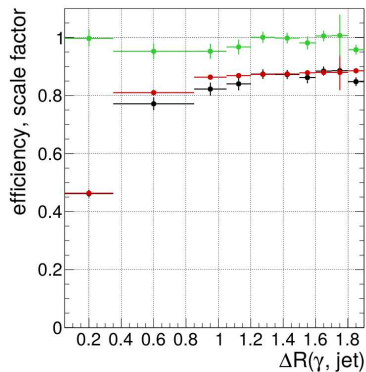


Figure : efficiency vs $\Delta R(\gamma, \text{jet})$ (data, MC, scale factor)

Figure : efficiency vs N_{PV} , (data, MC, scale factor)

- Overall scale factor = 0.985 ± 0.011 (Official values: 0.983 ± 0.012).



Cross check on pure QCD background estimate:

- Fake samples are sideband to candidate sample.
- If there is no signal anywhere in the E_T^{miss} , expect the relative fraction of candidate and fake-fake sample should remain constant as a function of E_T^{miss} .
- We fit the $\gamma\gamma/ff$ ratio with a simple function (in the form $\exp(ax+b)$) in the control region ($E_T^{miss} < 100$ GeV).
- Extend this ratio in signal region and ratio \times ff in one bin gives the double photon estimate coming from pure QCD in that bin.
- We take the overall normalization from fake sample and the distribution from loose fake samples.

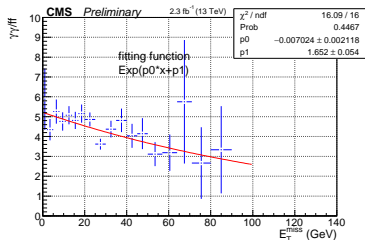


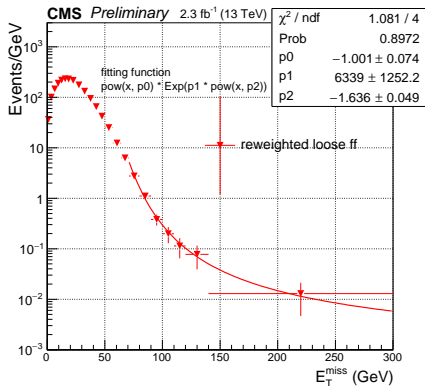
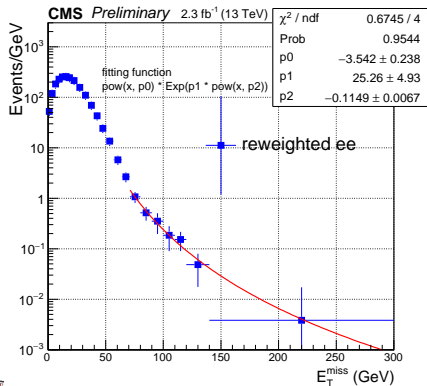
Table : Estimation of QCD background for $E_T^{miss} > 100$ GeV using the ff control sample

E_T^{miss} bin (GeV)	Method	Value
100 – 110	Di-EM p_T reweighting method	1.97 ± 0.69
	$\gamma\gamma/ff$ ratio method	1.12 ± 0.59
110 – 120	Di-EM p_T reweighting method	1.12 ± 0.48
	$\gamma\gamma/ff$ ratio method	0.61 ± 0.35
120 – 140	Di-EM p_T reweighting method	1.53 ± 0.76
	$\gamma\gamma/ff$ ratio method	0.68 ± 0.43
> 140	Di-EM p_T reweighting method	2.05 ± 1.32
	$\gamma\gamma/ff$ ratio method	0.91 ± 0.70

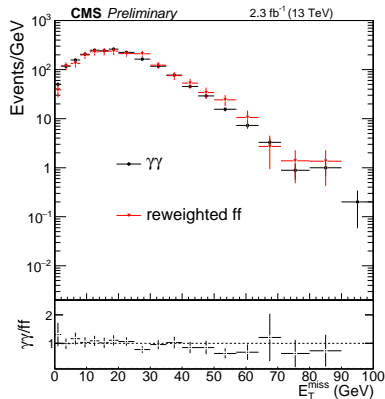
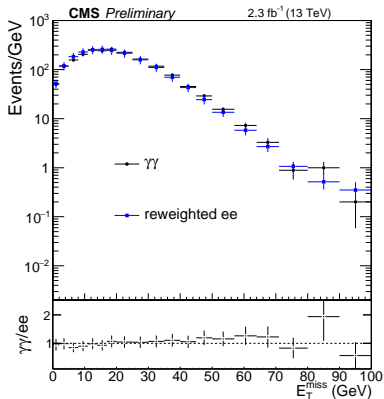


Shape difference between ee and ff E_T^{miss} distribution:

- Fit reweighted ee and ff E_T^{miss} distribution with $x^{p_0} \times \exp(p_1 \cdot x^{p_2})$, where p_0 , p_1 and p_2 are obtained from the fit in the range 70-300 GeV.
- Integrate each of the fits in the signal bins.
- Take the difference between the integrated results in each bin between ee and ff .
- Uncertainty in the last bin is large because here the integration range is high.



Comparison of reweighted control samples and data E_T^{miss}



Uncertainty in QCD background estimation:

Table : Shape uncertainty coming from the difference between the ee and ff E_T^{miss} distributions for $E_T^{miss} > 100$ GeV

E_T^{miss} bin (GeV)	ee prediction	ff prediction	difference	fractional difference
100 – 110	1.87	2.21	0.34	18.18%
110 – 120	1.16	1.30	0.14	12.07%
120 – 140	1.25	1.43	0.18	14.40%
> 140	1.39	3.48	2.09	150.36%

Table : Systematic and Statistical Uncertainties from QCD Background Estimation

E_T^{miss} bin (GeV)	Systematic Uncertainty	Value
100 – 110	Di-EM p_T reweighting	15.11%
	Jet multiplicity reweighting	33.77%
	Shape difference between ee and ff	18.18%
	Statistical uncertainty of ee sample	30.81%
110 – 120	Di-EM p_T reweighting	16.60%
	Jet multiplicity reweighting	14.87%
	Shape difference between ee and ff	12.07%
	Statistical uncertainty of ee sample	33.33%
120 – 140	Di-EM p_T reweighting	33.31%
	Jet multiplicity reweighting	29.39%
	Shape difference between ee and ff	14.40%
	Statistical uncertainty of ee sample	41.75%
140 – Inf	Di-EM p_T reweighting	39.37%
	Jet multiplicity reweighting	20.34%
	Shape difference between ee and ff	150.36%
	Statistical uncertainty of ee sample	70.98%



Other sources of systematic uncertainties:

Table : Summary of systematic uncertainties included in the determination of the expected exclusion contours.

Systematic Uncertainty	[%]
Integrated luminosity	4.6
Photon Data/MC scale factor	2.4
Jet energy scale	0 - 23
Finite MC statistics	0 - 16
PDF error on cross section	13 - 22



Table : Muon Medium Id

Muon

- $p_T > 30$ GeV.
- $|\eta| < 1.4442$.
- passes medium Id.

1. Global muon Normalized global-track χ^2 Tracker-Standalone position match Kick finder Segment compatibility	normalized $\chi^2 < 3$ χ^2 LocalPosition < 12 track Kink < 20 > 0.303
2. Tight segment compatibility	> 0.451

Jets

- $p_T > 30$ GeV and $|\eta| < 2.4$.
- Passes PFLoseld.
- Separated by $\Delta R > 0.4$ from all electrons, photons and muons.



Selection of objects: photon and electron

Photon

- $p_T > 40$ GeV
- Restricted to barrel region.
- passes medium Id.
- pixel seed = 0.

Electron

- Identical to photon selection except pixel seed match.

Table : 25 ns Spring 15 Cut-based Medium Photon Id

H/E	0.05
$\sigma_{i\eta i\eta}$	0.0102
ρ corrected charged hadron isolation	1.37
ρ corrected neutral hadron isolation	$1.06 + 0.014 \times p_T$ $+ 0.000019 \times p_T^2$
ρ corrected photon isolation	$0.28 + 0.0053 \times p_T$



Fake sample

- $p_T > 40$ GeV
- $|\eta| < 1.4442$
- $H/E < 0.05$
- Photon isolation and neutral hadron isolation from ID applied
- Passes pixel seed veto
- $R9 < 1.0$ and $\sigma_{i\eta i\eta} > 0.005$ to avoid spikes
- $0.0102 < \sigma_{i\eta i\eta} < 0.015$ XOR $1.37 < \text{Charged Isolation} < 15.0$

Loose Fake sample

- $p_T > 40$ GeV
- $|\eta| < 1.4442$
- $H/E < 0.05$
- Photon isolation and neutral hadron isolation from ID not applied
- Passes pixel seed veto
- $R9 < 1.0$ and $\sigma_{i\eta i\eta} > 0.005$ to avoid spikes
- $0.0102 < \sigma_{i\eta i\eta} < 0.020$ OR $1.37 < \text{Charged Isolation} < 40.0$

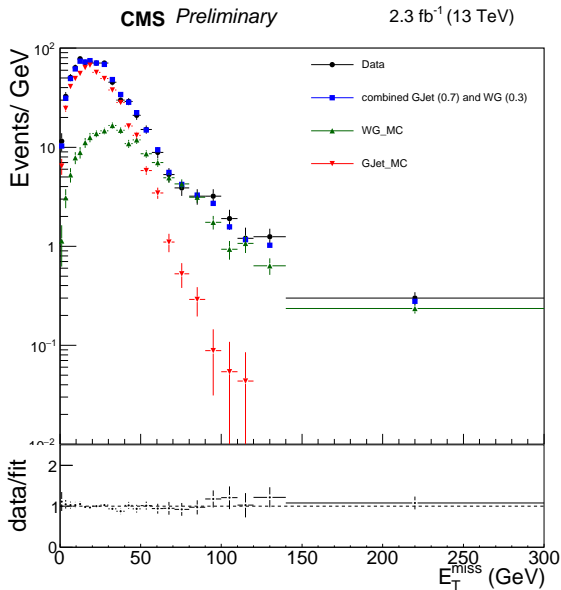


- $t\bar{t}$ sample where top decays leptonically:
 - Will have two electrons and E_T^{miss} due to neutrino.
 - In our ee control sample, we found 17.27 ± 0.98 events in the signal region from $t\bar{t}$.
 - We subtracted it's shape.
- $Z + jets$ sample where $Z \rightarrow \nu\nu$
 - In tight fake sample, we found only 0.1 events in the signal region. We neglected this.
 - In loose fake sample, we found 15.8 ± 0.9 events in the signal region. We also subtracted this shape.



- We find the number of observed $Z \rightarrow ee$ events in the ee mass spectrum as given by $N_{ee} = (1 - f_{e \rightarrow \gamma})^2 N_{trueZ}$ where N_{trueZ} is the true number of $Z \rightarrow ee$ events.
- the observed $Z \rightarrow ee$ peak in the $e\gamma$ mass spectrum is given by $N_{e\gamma} = 2[f_{e \rightarrow \gamma}(1 - f_{e \rightarrow \gamma})]N_{trueZ}$.
- We used single electron trigger: HLT_Ele27_eta2p1_WPLoose_Gsf
- The factor of 2 comes because we do not distinguish between $e\gamma$ events where electron has higher p_T compared to photon and vice versa.
- $f_{e \rightarrow \gamma} = N_{e\gamma} / (2N_{ee} + N_{e\gamma})$
- The number of events from the $e\gamma$ mass spectrum is given by $N_{e\gamma} = (1 - f_{e \rightarrow \gamma})N_{trueW}$ where N_{trueW} is the true $W\gamma$ events.
- Then in the $\gamma\gamma$ sample, the number of $N_{\gamma\gamma}$ coming from W background is given as:
 $N_{\gamma\gamma} = f_{e \rightarrow \gamma} N_{trueW} = N_{e\gamma} f_{e \rightarrow \gamma} / (1 - f_{e \rightarrow \gamma})$.





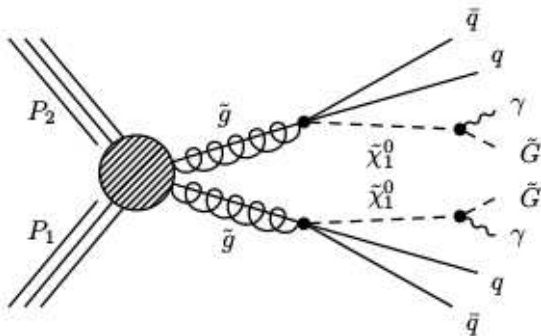
Effect of different cuts on signal point (1600, 800)

- total events: 13852
- events having two photons ($p_T > 0, 0$) : 3960
- events having two photons ($p_T > 30, 18$) : 3477
- events having two photons ($mass > 95$) : 3508
- events having two photons ($mass > 95, p_T > 30, 18$) : 3461
- events having two photons ($mass > 105, p_T > 30, 18$) : 3454
- events having two photons ($mass > 105, p_T > 40, 40$) : 3435



Simplified model:

- a limited set of hypothetical particles and decay chains are introduced
- this is to produce a given topological signature such as the diphoton final state studied in this analysis
- For gluino mass of 1.6 TeV and neutralino mass of 600 GeV, the event yield in the signal region: 4.58 and last bin is 4.41.



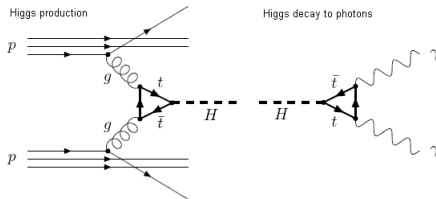


Figure : Higgs Boson decaying to two photons

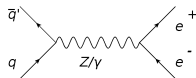


Figure : Z boson decaying to electrons

Standard Model $W\gamma$ production, Feynman Diagrams:

